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0521461960 - Photoinduced Defects in Semiconductors
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PHOTOINDUCED DEFECTS IN SEMICONDUCTORS

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CAMBRIDGE UNIVERSITY PRESS
 Cambridge, New York, Melbourne, Madrid, Cape Town, Singapore, São Paulo

Cambridge University Press
 The Edinburgh Building, Cambridge CB2 2RU, UK

Published in the United States of America by Cambridge University Press, New York

www.cambridge.org
 Information on this title: www.cambridge.org/9780521461962

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First published 1996
 This digitally printed first paperback version 2006

A catalogue record for this publication is available from the British Library

Library of Congress Cataloguing in Publication data

Redfield, David.

Photoinduced defects in semiconductors / David Redfield, Richard H. Bube.

p. cm. – (Cambridge studies in semiconductor physics
 and microelectronic engineering ; 4)

Includes index.

ISBN 0-521-46196-0 (hc)

1. Semiconductors – Defects. 2. Photochemistry.

I. Bube, Richard H., 1927–. II. Title. III. Series

QC611.6.D4R43 1996

621.3815'2 – dc20 95–32567

CIP

ISBN-13 978-0-521-46196-2 hardback

ISBN-10 0-521-46196-0 hardback

ISBN-13 978-0-521-02445-7 paperback

ISBN-10 0-521-02445-5 paperback